

<b>Notice of References Cited</b>	Application/Control No. 10/616,097		Applicant(s)/Patent Under Reexamination SUN ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2004/0072419	04-2004	Baskaran et al.	438/627
*	C	US-6,432,821	08-2002	Dubin et al.	438/678
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	K	US-			
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**NON-PATENT DOCUMENTS**

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